L Number	Hits	Search Text	DB	Time stamp
-	1	"878554"	US-PGPUB	2003/12/25 08:43
-	11	714/741.ccls.	US-PGPUB	2003/12/24 11:15
-	125	714/741.ccls.	USPAT; US-PGPUB	2003/12/24 11:17
-	13	714/741.ccls. and good with simulation	USPAT; US-PGPUB	2003/12/24 11:18
-	38	714/741.ccls. and (good reference) with simulation	USPAT; US-PGPUB	2003/12/25 07:47
-	40	714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating)	USPAT; US-PGPUB	2003/12/25 07:49
-	12	714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating) and ((fault defect) adj simulation)	USPAT; US-PGPUB	2003/12/25 07:52
-	12	714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating simulator) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 07:56
-	12	714/741.ccls. and ((logic circuit) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 07:57
-	12	714/741.ccls. and ((logic circuit logical) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:31
-	623	714/741.ccls. ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:20
-	33	714/741.ccls. and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:21
-	5	(714/741.ccls. and ((logic circuit logical) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))) not (714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating simulator) and ((fault defect) adj (simulation simulator)))	USPAT; US-PGPUB	2003/12/25 08:21
-	14	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:35
-	13	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults)	USPAT; US-PGPUB	2003/12/25 08:35
-	13	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults)	USPAT; US-PGPUB	2003/12/25 08:35
-	14	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects)	USPAT; US-PGPUB	2003/12/25 08:47
-	1	"878554" and value with node	US-PGPUB	2003/12/25 08:44
-	7	714/741.ccls. and ((l gic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulat r)) and (fault faults defect defects) and (node n des)	USPAT; US-PGPUB	2003/12/25 08:51

-	94	(((logic circuit I gical (fault adj free)) adj (simulati n simulat r)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node n des)) not (714/741.ccls. and ((I gic circuit logical (fault adj free)) adj (simulati n simulator)) and ((fault defect) adj (simulation simulat r)) and (fault faults defect defects) and (node nodes))	USPAT; US-PGPUB	2003/12/25 08:52
-	101	((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes)	USPAT; US-PGPUB	2003/12/25 09:06
-	106	((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 09:17
-	96	((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 11:43
-	10	(((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes)) not (((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 09:19
-	12	((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and (backtracing backtrace backtraced backtraces (back near (trace traces traced tracing)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 09:57
-	15	((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing ((back backward) near (trace traces traced tracing)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 10:01
-	15	((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing ((back backward) near (trace traces traced tracing drive)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 10:43

-	22	((l gic circuit logical (fault adj free)) adj (simulati n simulat r)) and ((fault defect) adj (simulati n simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing backtrack backtracks backtracking backtracked ((back backward) near (trace traces traced tracing drive track tracks tracking tracked)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 11:48
-	30	(simulation simulator) with ((fault faults) near (injection inject injecting injects injected))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 11:55
-	2	(simulation simulator) with ((fault faults defect defects) near (injection inject injecting injects injected)) and (node nodes) and ((test adj vector) pattern) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing ((back backward) near (trace traces traced tracing drive)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 10:44
-	44	((logic circuit logical (fault adj free) (good adj machine)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and scan	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 11:44
-	46	(((logic circuit logical (fault adj free)) adj (simulation simulator)) (good adj machine)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and scan	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 11:55
-	16	(((logic circuit logical (fault adj free)) adj (simulation simulator)) (good adj machine)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and ((partial full) adj scan)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/25 11:46
-	4	((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector) pattern) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing backtrack backtracks backtracking backtracked ((back backward) near (trace traces traced tracing drive track tracks tracking tracked))) and ((partial full) adj scan)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/26 07:12
-	7	(((logic circuit logical (fault adj free)) adj (simulation simulator)) (good adj machine)) and ((fault defect) adj (simulation simulator)) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing backtrack backtracks backtracking backtracked ((back backward) near (trace traces traced tracing drive track tracks tracking tracked))) and ((partial full) adj scan)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/26 07:11

-		1	(true adj value adj (simulati n simulator)) and ((fault defect) adj (simulation simulator)) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing backtrack backtracks backtracking backtracked ((back backward) near (trace traces traced tracing drive track tracks tracking tracked))) and ((partial full) adj scan)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/26 07:12
-		3	(simulation simulator) with ((fault faults) near (injection inject injecting injects injected)) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing backtrack backtracks backtracking backtracked ((back backward) near (trace traces traced tracing drive track tracks tracking tracked))) and ((partial full) adj scan)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/26 07:12